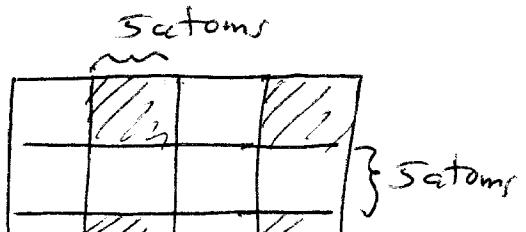


2. (1)

Hwk #2

1.

Top View

 $\square = Ge$ $\square = Si$

\rightarrow similarly in vertical (2) direction.

$\xleftarrow{\text{Up repeat period}}$

repeat period

$$L_p = L_{Si} + L_{Ge}$$

5x atomic spacing

$$= 5d_{Si} + 5d_{Ge}$$

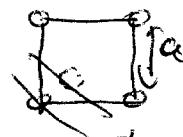
$$d_{Si} = \frac{\sqrt{3}}{4} a_{Si}$$

a = Cubic lattice constant

$$= 0.5431 \text{ nm } Si$$

$$0.5658 \text{ nm } Ge$$

$$d_{Si} = 0.235 \text{ nm}$$



$$d_{Ge} = \frac{\sqrt{3}}{4} \times 0.5658 \text{ nm} = 0.245 \text{ nm}$$

$$\begin{aligned} \text{so } L_{\text{period}} &= 5 \times 0.235 \text{ nm} + 5 \times 0.245 \text{ nm} \\ &= 2.4 \text{ nm} \quad \text{per Si+ that consists of Ge dot surrounded by Si.} \end{aligned}$$

a) Surface Si+ density:

$$1.5 \text{ t}/(2.4 \text{ nm})^2 = 1.736 \times 10^{13} \text{ cm}^{-2}$$

$$= 17.36 \text{ Terabits/cm}^2 = \rho^{20}$$

b) volume density

$$1.5 \text{ t}/(2.4 \text{ nm})^3 = 7.23 \times 10^{19} \text{ cm}^{-3} = \rho^{30}$$

c) area for 1 Terabit; $8.15 = \rho^{20} \times A$

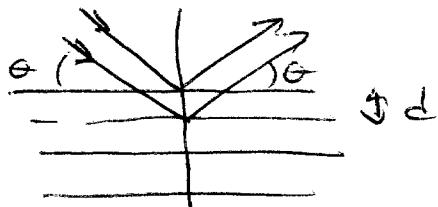
$$A_{IT} = \frac{1 \text{ Tbit}}{17.36 \text{ Tbits/cm}^2} = \frac{1}{17.36} \text{ cm}^2 = 0.0576 \text{ cm}^2$$

d) Bit in $1\text{cm}^2 \times 10$ layers.

$$\begin{aligned} B_{\text{bit}} &= 17.36 \text{ Tbits/cm}^2 \times 10 \text{ periods} \\ &= 173.6 \text{ Tbits} \end{aligned}$$

L
2.]

Bragg diffraction $2d \sin \theta = n\lambda$



$$\theta = \sin^{-1} \frac{n\lambda}{2d}$$

$\sqrt{2}/2$

$$\lambda = \frac{2d \sin \theta}{(n=\text{order})} = \frac{2 \times 2.4 \text{ nm} \overbrace{\sin 45^\circ}}{n}$$

c) $\lambda = 3.394 \text{ nm}$ for 1st order ($n=1$) at 45°
for every bit active (1111... pattern)

b) If it were possible to turn every other bit off (1010...) then diffraction $\rightarrow 2d$

$$\begin{aligned} \theta &= \sin^{-1} \frac{3.394 \text{ nm}}{2 \times 2.4 \text{ nm}} = \sin^{-1}[0.3535] \\ &= 20.7^\circ \end{aligned}$$

c) for $\lambda_{\text{CuK}\alpha} = 0.154 \text{ nm} = 1.54 \text{ \AA}$

$$\theta = \sin^{-1} \left[\frac{0.154 \text{ nm}}{2 \times 2.4 \text{ nm}} \right] = \sin^{-1}(0.0321) = 1.84^\circ$$

d) It seems that X-rays could diffract from the quantum dot bit pattern

3]

assume that the 20 nm refers to L_G

$$w = 5 L_G = 100 \text{ nm}$$

$$t_{ox} = 0.8 \text{ nm} = 8 \text{ Å}$$

a) $f_T = \frac{v_{sat}}{2\pi L_g} \rightarrow v_{sat} = 2\pi L_g f_T$
 $= 1.5 \text{ THz}$

$$v_{sat} = 2\pi \times 20 \text{ nm} \times 1.5 \text{ THz} \\ = 1.885 \times 10^7 \text{ cm/sec}$$

b) this is realistic because v_{sat} for Si
 $v_{sat} \sim 1 \text{ to } 2 \times 10^7 \text{ cm/sec}$

c) how many e^- on gate with $V_{GJ} - V_T = 1 \text{ volt}$.

$$C_{ox} = \frac{K_ox \epsilon}{t_{ox}} = \frac{3.9 \times 8.85 \times 10^{-14} \text{ F/cm}}{0.8 \times 10^{-7} \text{ cm}} \\ = 4.3 \times 10^{-6} \text{ F/cm}^2 = 4.3 \frac{10^{-6} \text{ F}}{10^8 \mu\text{m}^2 = 1 \text{ cm}^2} \\ = 43 \text{ fF}/\mu\text{m}^2$$

d) $C = \frac{\Delta Q}{\Delta V} \quad Q = qN = CV$

$$N = \frac{43 \text{ fF}/\mu\text{m}^2}{q = 1.6 \times 10^{-19} \text{ C}} \times 1 \text{ V} \times (20 \text{ nm} \times 100 \text{ nm})$$

$$N_{\text{gate}} = 539 \text{ electrons}$$